



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16738Generic Copy

Issue Date: 13-Oct-2011

TITLE: Final Notification for Transfer of Zener Filtering products from Sanyo fab in Japan to ON Semiconductor, Pocatello (ID) Fab in United State.

PROPOSED FIRST SHIP DATE: 13-Jan-2012 or earlier with customer approval.

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Fab Site

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Yew Hee Soon < y.soon@onsemi.com >

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Francis Lualhati < ffxczy@onsemi.com >

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

ON Semiconductor is notifying customers of its plan to transfer fabrication of Zener Filtering products from Sanyo fab in Japan, to ON Semiconductor Fab 10 located in Pocatello, ID (USA).

Description of the change:

The transfer and qualification of the Zener Z1A process and the associated integrated circuits from the Sanyo facility in Japan to the Fab 10 wafer fabrication site located in the Pocatello, Idaho.

The Fab 10 facility is an ON Semiconductor owned wafer fab that has been producing products since 2000 (formerly as AMI). Several existing technologies within ON Semiconductor's product families are currently sourced from Fab 10, including CMOS and LVFR products. The Fab 10 Pocatello site is certified according to ISO9001:2008, 14001:2004, ISO/TS 16949:2009 and AS 9100B standards as well as MIL-PRF-38535, CTPAT and STACK.

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Qualification tests are designed to show that the reliability of transferred devices will continue to meet or exceed ON Semiconductor standards.

Devices listed in this final PCN should be transferred to ON Semiconductor Fab 10 in Pocatello starting Nov 2011. After 8 Nov 2011, customer may receive devices from either facility. Parts are identifiable by date code 1202 (YYWW).

RELIABILITY DATA SUMMARY:**Reliability Test Results for CM1442-08CP:**

Test:	Conditions:	Interval:	Results		
HTRB	TA = 125°C, bias=80% rated V or 100V Max	1008 hrs	0/80	0/80	0/80
HTSL	Ta=150°C	1008 hrs	0/80	0/80	0/80
UHASt	Ta=130°C, RH=85%	96 hrs	0/80	0/80	0/80
TC	Ta= -40/125°C	1000 cyc	0/80	0/80	0/80
AC	Ta=+121°C, RH=100%, P=15psig,	96 hrs	0/80	0/80	0/80
CDPA	After Post TC		0/3	0/3	0/3

Conclusion: All reliability requirements have been met.

ELECTRICAL CHARACTERISTIC SUMMARY:

Available upon request

CHANGED PART IDENTIFICATION:

There will be no changes to standard device markings. Normal assembly lot traceability codes will identify the wafer fab source.



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List of affected General Parts:

PART

CM1443-04CP

CM1443-08CP

CM1242-33CP